# PMN50XP

# P-channel TrenchMOS extremely low level FET

Rev. 02 — 2 October 2007

Product data sheet

## 1. Product profile

### 1.1 General description

Extremely low level P-channel enhancement mode Field-Effect Transistor (FET) in a plastic package. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

### 1.2 Features

■ Low on-state losses

Low threshold voltage

## 1.3 Applications

Battery management

Battery powered portable equipment

Load Switching

Low power DC to DC converters

### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25~^{\circ}C;~T_j \le 150~^{\circ}C$	-	-	-20	V
I <sub>D</sub>	drain current	$V_{GS}$ = -4.5 V; $T_{sp}$ = 25 °C; see <u>Figure 1</u> and <u>3</u>	-	-	-4.8	Α
Dynamic	c characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = -4.5 \text{ V}; I_D = -4.7 \text{ A};$ $V_{DS} = -10 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	1.3	-	nC
Static ch	naracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = -4.5 V; $I_D$ = -2.8 A; $T_j$ = 25 °C; see <u>Figure 7</u> and <u>8</u>	-	48	60	mΩ





## 2. Pinning information

Table 2. Pinning

Pin	Symbol	Description	Simplified outline	Graphic Symbol
1	D	drain	□6 □5 □4	D
2	D	drain		
3	G	gate	0	
4	S	source	1 2 3	G—Vi
5	D	drain		S
6	D	drain		003aaa671

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PMN50XP	TSOP6	plastic surface-mounted package (TSOP6); 6 leads	SOT457

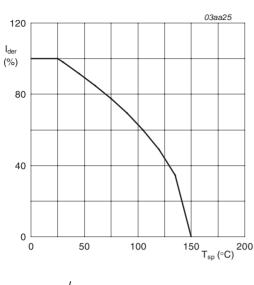
# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

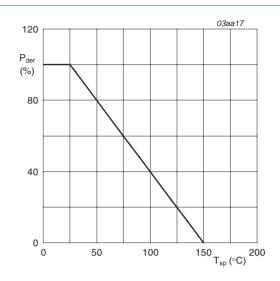
Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25  ^{\circ}C;  T_j \le 150  ^{\circ}C$	-	-20	V
$V_{DGR}$	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	-20	V
$V_{GS}$	gate-source voltage		-12	12	V
$I_D$	drain current	$T_{sp}$ = 25 °C; $V_{GS}$ = -4.5 V; see <u>Figure 1</u> and <u>3</u>	-	-4.8	Α
		$T_{sp} = 100  ^{\circ}C;  V_{GS} = -4.5  V$	-	-3	Α
$I_{DM}$	peak drain current	$T_{sp}$ = 25 °C; $t_p$ < 10 $\mu s$ ; pulsed; see <u>Figure 3</u>	-	-19.4	Α
P <sub>tot</sub>	total power dissipation	$T_{sp} = 25 ^{\circ}C$ ; see <u>Figure 2</u>	-	2.2	W
T <sub>stg</sub>	storage temperature		-55	150	°C
T <sub>j</sub>	junction temperature		-55	150	°C
Source-o	drain diode				
Is	source current	T <sub>sp</sub> = 25 °C	-	-1.9	Α
I <sub>SM</sub>	peak source current	$T_{sp}$ = 25 °C; $t_p \le 10 \mu s$ ; pulsed	-	-7.5	А

PMN50XP\_2 © NXP B.V. 2007. All rights reserved.



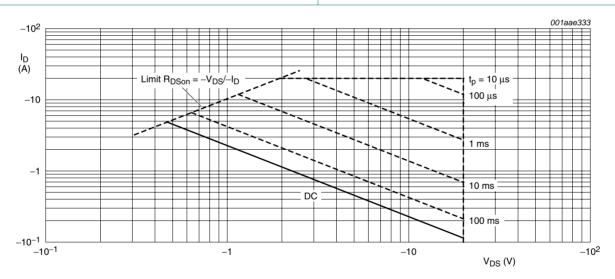
$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 1. Normalized continuous drain current as a function of solder point temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25\,^{\circ}\text{C})}} \times 100\,\%$$

Fig 2. Normalized total power dissipation as a function of solder point temperature



 $T_{sp}$  = 25 °C;  $I_{DM}$  is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

3 of 11

NXP Semiconductors PMN50XP

### P-channel TrenchMOS extremely low level FET

## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point	see Figure 4	-	-	55	K/W

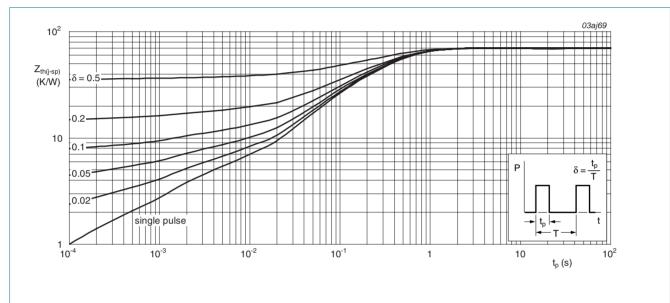


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration

## 6. Characteristics

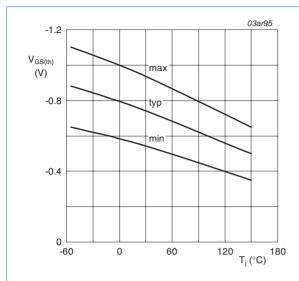
Table 6. Characteristics

Parameter	Conditions	Min	Тур	Max	Unit
racteristics					
drain-source breakdown voltage	$I_D = -250 \mu A; V_{GS} = 0 V;$ $T_j = 25 ^{\circ}C$	-20	-	-	V
	$I_D = -250 \mu A; V_{GS} = 0 V;$ $T_j = -55 ^{\circ}C$	-18	-	-	V
gate-source threshold voltage	$I_D$ = -0.25 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C; see <u>Figure 5</u> and <u>6</u>	-0.55	-0.75	-0.95	V
	$I_D$ = -0.25 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 150 °C; see <u>Figure 5</u> and <u>6</u>	-0.35	-	-	V
	$I_D$ = -0.25 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; see <u>Figure 5</u> and <u>6</u>	-	-	-1.1	V
drain leakage current	$V_{DS} = -20 \text{ V}; V_{GS} = 0 \text{ V};$ $T_j = 25 ^{\circ}\text{C}$	-	-	-1	μА
	$V_{DS} = -20 \text{ V}; V_{GS} = 0 \text{ V};$ $T_j = 70 \text{ °C}$	-	-	-5	μА
	drain-source breakdown voltage gate-source threshold voltage	drain-source breakdown voltage $I_D = -250 \ \mu A; \ V_{GS} = 0 \ V;$ $T_j = 25 \ ^{\circ}C$ $I_D = -250 \ \mu A; \ V_{GS} = 0 \ V;$ $T_j = -55 \ ^{\circ}C$ $gate\text{-source threshold}$ $voltage I_D = -0.25 \ mA; \ V_{DS} = V_{GS};$ $T_j = 25 \ ^{\circ}C; \ see \ \underline{Figure 5} \ and \ \underline{6}$ $I_D = -0.25 \ mA; \ V_{DS} = V_{GS};$ $T_j = 150 \ ^{\circ}C; \ see \ \underline{Figure 5} \ and \ \underline{6}$ $I_D = -0.25 \ mA; \ V_{DS} = V_{GS};$ $T_j = -55 \ ^{\circ}C; \ see \ \underline{Figure 5} \ and \ \underline{6}$ $V_{DS} = -20 \ V; \ V_{GS} = 0 \ V;$ $T_j = 25 \ ^{\circ}C$ $V_{DS} = -20 \ V; \ V_{GS} = 0 \ V;$	$\begin{array}{ll} \text{drain-source} & I_D = -250 \ \mu\text{A}; \ V_{GS} = 0 \ \text{V}; & -20 \\ \text{breakdown voltage} & T_j = 25 \ ^{\circ}\text{C} \\ & I_D = -250 \ \mu\text{A}; \ V_{GS} = 0 \ \text{V}; & -18 \\ & T_j = -55 \ ^{\circ}\text{C} \\ \end{array}$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	$ \begin{array}{l} \text{drain-source} \\ \text{breakdown voltage} \end{array} \begin{array}{l} I_D = -250 \ \mu \text{A; V}_{GS} = 0 \ \text{V;} \\ T_j = 25 \ ^{\circ}\text{C} \end{array} \begin{array}{l} -20 \ - \ - \ - \ - \ - \ - \ - \ - \ - \ $

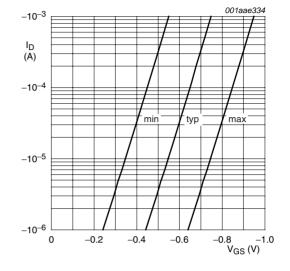
PMN50XP\_2 © NXP B.V. 2007. All rights reserved.

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$I_{GSS}$	gate leakage current	$V_{GS} \leq$ 12 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	-10	-100	nA
		$V_{GS} \geq 12 \text{ V; } V_{DS} = 0 \text{ V; } T_j = 25 ^{\circ}\text{C}$	-	-10	-100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = -4.5 \text{ V}; I_D = -2.8 \text{ A};$ $T_j = 25 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 7}}{2} \text{ and } \frac{8}{2}$	-	48	60	mΩ
		$V_{GS} = -4.5 \text{ V}; I_D = -2.8 \text{ A};$ $T_j = 150 \text{ °C}; \text{ see } \frac{\text{Figure 7}}{\text{Im}} \text{ and } \frac{8}{\text{M}}$	-	77	96	mΩ
		$V_{GS} = -2.5 \text{ V}; I_D = -2.3 \text{ A};$ $T_j = 25 ^{\circ}\text{C}; \text{ see } \frac{\text{Figure 7}}{\text{Figure 7}} \text{ and } \frac{8}{\text{M}}$	-	65	80	mΩ
Dynamic c	haracteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = -4.7 \text{ A}; V_{DS} = -10 \text{ V};$ $V_{GS} = -4.5 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	10	-	nC
$Q_{GS}$	gate-source charge	$I_D = -4.7 \text{ A}; V_{DS} = -10 \text{ V};$ $V_{GS} = -4.5 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	2.2	-	nC
$Q_{GD}$	gate-drain charge	$I_D = -4.7 \text{ A}; V_{DS} = -10 \text{ V};$ $V_{GS} = -4.5 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	1.3	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS}$ = -20 V; $V_{GS}$ = 0 V; f = 1 MHz; $T_j$ = 25 °C; see <u>Figure 11</u>	-	1020	-	pF
C <sub>oss</sub>	output capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = -20 \text{ V};$ $f = 1 \text{ MHz}; T_j = 25 ^{\circ}\text{C};$ see Figure 11	-	140	-	pF
C <sub>rss</sub>	reverse transfer capacitance	$V_{DS}$ = -20 V; $V_{GS}$ = 0 V; f = 1 MHz; $T_j$ = 25 °C; see <u>Figure 11</u>	-	100	-	pF
$t_{d(on)}$	turn-on delay time	$R_{G(ext)} = 6 \Omega; R_L = 10 \Omega;$ $V_{DS} = -10 V; V_{GS} = -4.5 V;$ $T_j = 25 °C$	-	8.5	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 6 \Omega$ ; $R_L = 10 \Omega$ ; $V_{DS} = -10 V$ ; $V_{GS} = -4.5 V$ ; $T_j = 25 ^{\circ}C$	-	7.5	-	ns
$t_{d(off)}$	turn-off delay time	$V_{DS} = -10 \text{ V}; R_L = 10 \Omega;$ $V_{GS} = -4.5 \text{ V}; R_{G(ext)} = 6 \Omega;$ $T_j = 25 \text{ °C}$	-	82	-	ns
t <sub>f</sub>	fall time	$R_{G(ext)} = 6 \Omega$ ; $R_L = 6 \Omega$ ; $V_{DS} = -10 V$ ; $V_{GS} = -4.5 V$ ; $T_j = 25 °C$	-	35	-	ns
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = -10 \text{ V; } I_{D} = -4.7 \text{ A;}$ $T_{j} = 25 \text{ °C; see } \frac{\text{Figure 9}}{\text{Figure 9}} \text{ and } \frac{10}{\text{ N}}$	-	-1.6	-	V
Source-dra	ain diode					
$V_{SD}$	source-drain voltage	$I_S = -1.7 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-0.77	-1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 3.5 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ; $V_{DS} = 20 \text{ V}$ ; $T_i = 25 ^{\circ}\text{C}$	-	-	-	ns



 $I_D = -0.25 \text{ mA}; V_{DS} = V_{GS}$ 



$$T_i = 25 \, ^{\circ}C; V_{DS} = -5 \, V$$

Fig 5. Gate-source threshold voltage as a function of junction temperature



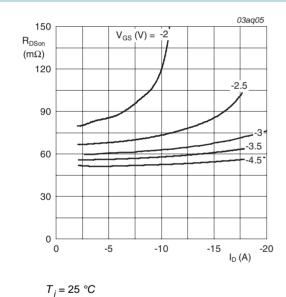
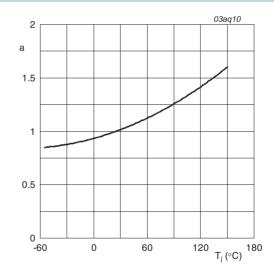


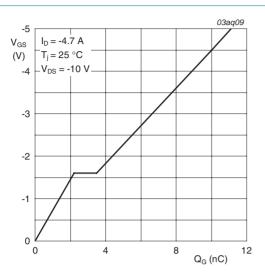
Fig 7. Drain-source on-state resistance as a function of drain current; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



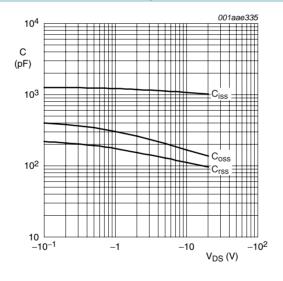


$$I_D = -4.7 \text{ A}; T_i = 25 \text{ °C}; V_{DS} = -10 \text{ V}$$

V<sub>DS</sub> V<sub>GS(pl)</sub> V<sub>GS(th)</sub> V<sub>GS(th)</sub> Q<sub>GS1</sub> Q<sub>GS2</sub> Q<sub>G</sub>(tot) 003aaa508

Fig 10. Gate charge waveform definitions

# Fig 9. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$ ; f = 1 MHz

Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

## 7. Package outline

### Plastic surface-mounted package (TSOP6); 6 leads

**SOT457** 

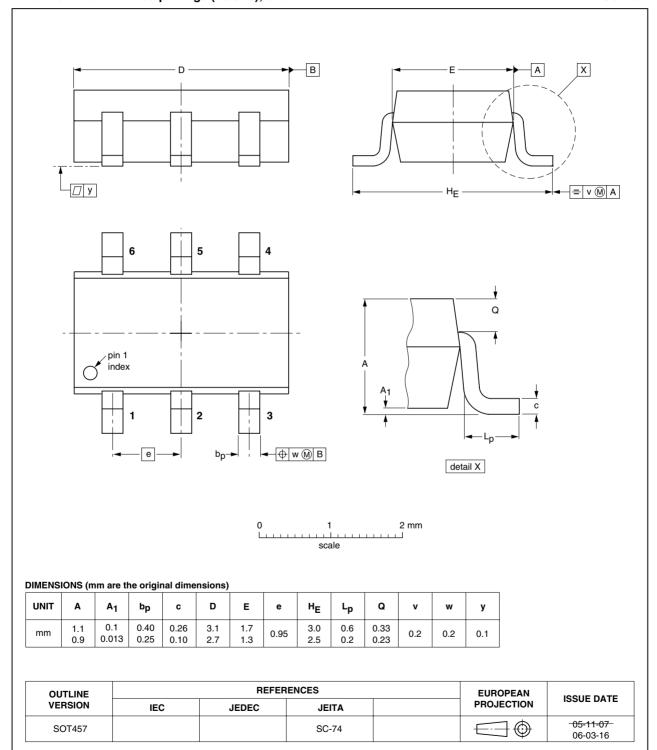


Fig 12. Package outline SOT457 (TSOP6)



9 of 11

## P-channel TrenchMOS extremely low level FET

## **Revision history**

#### Table 7. **Revision history**

**Product data sheet** 

Document ID	Release date	Data sheet status	Change notice	Supersedes
PMN50XP_2	20071002	Product data sheet	-	PMN50XP_1
Modifications:		of this data sheet has beer of NXP Semiconductors.	n redesigned to comply v	vith the new identity
	<ul> <li>Legal texts</li> </ul>	have been adapted to the	company name where a	opropriate.
PMN50XP_1	20060123	Product data sheet	-	-

NXP Semiconductors PMN50XP

### P-channel TrenchMOS extremely low level FET

## 9. Legal information

### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

### 9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

#### 9.3 Disclaimers

**General** — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of a NXP Semiconductors product can reasonably be expected to

result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <a href="http://www.nxp.com/profile/terms">http://www.nxp.com/profile/terms</a>, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

**No offer to sell or license** — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

### 9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

### 10. Contact information

For additional information, please visit: http://www.nxp.com

For sales office addresses, send an email to: <a href="mailto:salesaddresses@nxp.com">salesaddresses@nxp.com</a>

PMN50XP 2 © NXP B.V. 2007. All rights reserved.

**NXP Semiconductors** 



### P-channel TrenchMOS extremely low level FET

## 11. Contents

1	Product profile
1.1	General description
1.2	Features
1.3	Applications
1.4	Quick reference data 1
2	Pinning information 2
3	Ordering information 2
4	Limiting values 2
5	Thermal characteristics 4
6	Characteristics 4
7	Package outline 8
8	Revision history 9
9	Legal information 10
9.1	Data sheet status
9.2	Definitions
9.3	Disclaimers
9.4	Trademarks 10
10	Contact information 10
11	Contents 11

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.





founded by